

IMPORTANT DATES

- Submission Deadline**
October 10, 2026 (Final Call !!!)
- Notification of Acceptance**
October 25, 2026
- Registration Deadline**
November 1, 2026

Session Keynote Lectures



Emmanuel Fragnière
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Valais-Wallis (HES-SO), Switzerland



Yuantao Yao
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Politecnico di Torino, Italy



Sylwia Werbinska-Wojciechowska
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Alba Sofi
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Yanhua Zou
Wuxi University, China



Elena Zaitseva
University of Zilina, Slovakia



Prabhakar Varde
SRESA, India



Tangfan Xiahou
University of Electronic Science
Technology of China, China



He Li, Liverpool John
Moores University, UK



Jeroen Boydens
KU Leuven, Belgium



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Janet Lin
VP of IEEE Reliability



Masoud Naseri
University of Tromsø, Norway



Rui He
University of Electronic Science and
Technology of China, China



Hao Rong
Liverpool John Moores University, UK

Welcome to the 10th Anniversary of ICSRS 2026!

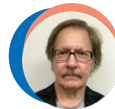
The 10th International Conference on System Reliability and Safety (ICSRS 2026) will take place from November 23-25, 2026, in Rome, Italy, and is technically co-sponsored by Politecnico di Milano, Italy and IEEE Reliability Society (Italy Chapter). The conference provides a platform for researchers, practitioners, and industry experts to exchange ideas and present their latest research findings on various topics, including fault diagnosis, fault-tolerant control, risk analysis, safety management, system reliability assessment, and maintenance optimization. The conference will facilitate the exchange of ideas and foster the development of new techniques and methodologies to improve system reliability and safety, ultimately contributing to the creation of a safer and more reliable world.

Publication Support

All accepted papers must be written in English and will be published into ICSRS 2026 Conference Proceedings. The Conference content will be submitted for inclusion into IEEE Xplore as well as other Abstracting and Indexing (A&I) databases. The proceedings is expected to be indexed by Scopus & EI Compendex, etc.

MDPI has announced the 10th ICSRS:
<https://www.mdpi.com/journal/jne/events/19963>

Plenary Speakers



Michael Pecht
University of
Maryland, USA



Michael Beer
Hannover University,
Germany



Luca Podofillini
Paul Scherrer Institute,
Switzerland

Topics

Track 1: System Design and Modeling Based on Reliability

Chairs: **Mariagrazia Fugini, Politecnico di Milano, Italy**
Matteo Davide Lorenzo Dalla Vedova, Politecnico di Torino, Italy
Matthieu Martel, LAMPS Perpignan University, France

Data-driven reliability model design
Design Optimization Using R&M Techniques
Discrete Event Modeling & Simulation
Condition monitoring, diagnostics and prognostics

Track 2: Machine Learning and Data Analysis in Reliable Engineering

Chairs: **Chao Zhao, Northeastern University, China**
Myrto Konstantinidou, National Center for Scientific Research "Demokritos", Greece

Fault Tree Analysis
Reliability testing and statistics
Big-Data Supported Reliability Assessment
Fault tolerance and diagnosis

Track 3: Product Reliability Assessment and Management

Chairs: **Fabrizio Baiardi, Università di Pisa, Italy**
Yiliu Liu, Norwegian University of Science and Technology, Norway
Polinapapilinho Katina, University of South Carolina Upstate, USA
Horst Lewitschnig, Infineon Technologies, Austria

Reliability theory and application
Structural reliability
Risk assessment & management
Product reliability and safety evaluation

Track 4: Engineering Reliability Maintenance and Safety Management

Chairs: **Izabela Piegdon, Rzeszow University of Technology, Poland**
Elena Stefana, Sapienza University of Rome, Italy
Bako Rajaaonah, University Polytechnique Hauts-de-France, France
Gloria Gori, Università di Firenze - DINFO, Italy

Strategic asset management
Asset fleet management
Quality engineering
Quality assurance and cost issues

Submission Instruction

- Full paper: Presentation and Publication
 - Abstract: Presentation only
- Submission System: <https://www.easychair.org/conferences/?conf=icsrs2026> (.pdf only)
Conference Proceeding Template: <https://www.icsrs.org/instruct8.5x11x2.doc> (word)
<https://www.icsrs.org/ieee-latex-conference-template.zip> (latex)
The paper length is within 4-10 pages (One regular registration can cover a paper within 5 pages). Official language is English in paper writing and presenting.

Special Session

SS 1: Balancing AI-Driven Safety and AI-Induced Risks in Integrated Nuclear Systems

Chairs: Katrina Groth, University of Maryland, US
Jun Yang, South China University of Technology, China
Mengchu Song, Shenzhen Technology University, China
Ruixue Li, University of Maryland, US
Hidekazu Yoshikawa, Kyoto University, Japan
Takeshi Matsuo, Utsunomiya University, Japan

SS 2: Belief reliability for complex systems: Uncertainty management and safety assurance

Chairs: Xiaoyang Li, Beihang University, China
Qingyuan Zhang, Hangzhou International Innovation Institute of Beihang University, China
Waichon Lio, Beihang University, China

SS 3: AI-Augmented Predictive Maintenance for Complex Industrial Systems

Chairs: Yang Li, Beihang University, China
Lanxiang Liu, Harbin Institute of Technology, China
Bin Wang, Wuhan University of Technology, China

SS 4: Trustworthy Agentic Intelligence for PHM-Oriented Industrial Reliability and Safety

Chairs: Diyin Tang, Beihang University, China
Danyang Han, Aerospace Information Technology University, China

SS 5: Physics-Informed AI for Health Monitoring, Reliability, and Uncertainty Quantification

Chair: Cheng Liu, City University of Hong Kong, China

SS 6: Industrial Reliability Analysis and Optimization under Limited Data

Chairs: Yu Liu, University of Electronic Science and Technology of China, China
Rui He, University of Electronic Science and Technology of China, China
Qin Zhang, University of Electronic Science and Technology of China, China
Kai Wang, Université Paris-Saclay, France

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